

Special Issue

Electromagnetic Imaging from Radio Frequency to Sub-millimeter Waves

Message from the Guest Editors

The objective of electromagnetic imaging is to retrieve information about tested structures by studying their interactions with electromagnetic waves. To make a long story short, this involves solving an inverse problem, where the measurable effect is a field-related quantity, and the cause is related to the targets' geometric and electromagnetic properties. The major benefit of using non-ionizing radiation for electromagnetic imaging is the possibility of acquiring target features and analyzing objects in a fully non-invasive and safe way. Topics of interest include, but are not limited to:

- Electromagnetic imaging
- Microwave imaging
- Millimeter-Wave imaging
- THz imaging
- Tomography
- Inverse scattering
- Inverse problems
- Subsurface imaging
- Nondestructive tests
- Through-the-Wall imaging
- Biomedical diagnostics
- Security imaging

Guest Editors

Dr. Alessandro Fedeli

Department of Electrical, Electronic, Telecommunication Engineering, and Naval Architecture, University of Genoa, 16145 Genova, Italy

Dr. Valentina Schenone

Department of Electrical, Electronic, Telecommunications Engineering, and Naval Architecture, University of Genoa, 16145 Genova, Italy

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Electronics
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
electronics@mdpi.com

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Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guestedited by leading experts in selected topics of interest.

Editor-in-Chief

Prof. Dr. Flavio Canavero

Department of Electronics and Telecommunications, Politecnico di
Torino, 10129 Torino, Italy

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